#### SN54LV374, SN74LV374 OCTAL EDGE-TRIGGERED D-TYPE FLIP-FLOPS WITH 3-STATE OUTPUTS SCLS197B – FEBRUARY 1993 – REVISED APRIL 1996

EPIC ™ (Enhanced-Performance Implanted CMOS) 2-µ Process

- Typical V<sub>OLP</sub> (Output Ground Bounce)
   < 0.8 V at V<sub>CC</sub>, T<sub>A</sub> = 25°C
- Typical V<sub>OHV</sub> (Output V<sub>OH</sub> Undershoot)
   > 2 V at V<sub>CC</sub>, T<sub>A</sub> = 25°C
- ESD Protection Exceeds 2000 V Per MIL-STD-883C, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JEDEC Standard JESD-17
- Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DB), Thin Shrink Small-Outline (PW), Ceramic Flat (W) Packages, Chip Carriers (FK), and (J) 300-mil DIPs

### description

These octal edge-triggered D-type flip-flops are designed for 2.7-V to 5.5-V  $\rm V_{CC}$  operation.

The 'LV374 feature 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. These devices are particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

SN74LV374DB, DW, OR PW PACKAGE (TOP VIEW)										
OE 1Q 1D 2D 2Q 3Q 3D 4D 4D 4Q GND	$ \begin{bmatrix} 1 \\ 2 \\ 3 \\ 4 \\ 5 \\ 6 \\ 7 \\ 8 \\ 9 \\ 10 \end{bmatrix} $	20 ] 19 ] 18 ] 17 ] 16 ] 15 ] 14 ] 13 ] 12 ] 11 ]	V <sub>CC</sub> 8Q 8D 7D 7Q 6Q 6D 5D 5Q CLK							

SN54LV374 . . . J OR W PACKAGE

SN54LV374 . . . FK PACKAGE (TOP VIEW)

	10 0 <u>1</u> 80 80
2D 2Q 3Q 3D 4D	3       2       1       20       19       8D         4       18       8D         5       17       7D         6       16       7Q         7       15       6Q         8       14       6D         9       10       11       12
	50 40 50 50 50 50 50 50 50 50 50 50 50 50 50 5

On the positive transition of the clock (CLK) input, the Q outputs are set to the logic levels set up at the data (D) inputs.

A buffered output-enable ( $\overline{OE}$ ) input can be used to place the eight outputs in either as normal logic state (high or low logic levels) or high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and the increased drive provide the capability to drive bus lines without need for interface or pullup components.

OE does not affect internal operations of the latch. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

The SN74LV374 is available in TI's shrink small-outline package (DB), which provides the same I/O pin count and functionality of standard small-outline packages in less than half the printed-circuit-board area.

The SN54LV374 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74LV374 is characterized for operation from –40°C to 85°C.



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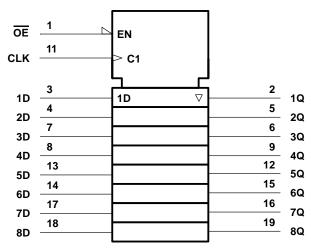


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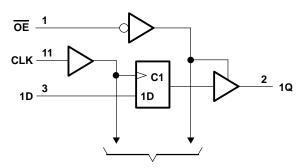
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FUNCTION TABLE (each flip-flop)										
	INPUTS	OUTPUT								
OE	CLK	D	Q							
L	$\uparrow$	Н	Н							
L	$\uparrow$	L	L							
L	L	Х	Q <sub>0</sub>							
Н	Х	Х	Z							

### logic symbol<sup>†</sup>



logic diagram (positive logic)



**To Seven Other Channels** 

<sup>+</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for DB, DW, J, PW, and W packages.

#### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>‡</sup>

Supply voltage range, $V_{CC}$ Input voltage range, $V_I$ (see Note 1)	$\begin{array}{c} 0.5 \mbox{ V to } V_{CC} + 0.5 \mbox{ V} \\ 0.5 \mbox{ V to } V_{CC} + 0.5 \mbox{ V} \\ \dots & \pm 20 \mbox{ mA} \\ \dots & \pm 50 \mbox{ mA} \\ \dots & \pm 35 \mbox{ mA} \\ \dots & \pm 70 \mbox{ mA} \\ \dots & \dots & 0.6 \mbox{ W} \\ \dots & \dots & 1.6 \mbox{ W} \end{array}$
PW package	

<sup>‡</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

- 2. This value is limited to 7 V maximum.
- 3. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils.



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#### recommended operating conditions (see Note 4)

			SN54L	.V374	374 SN74LV374		LINUT	
			MIN	MAX	MIN	MAX	UNIT	
VCC	Supply voltage		2.7	5.5	2.7	5.5	V	
V	High-level input voltage	$V_{CC} = 2.7 V \text{ to } 3.6 V$	2		2		V	
VIH		$V_{CC} = 4.5 V \text{ to } 5.5 V$	3.15		3.15		v	
\/	Low-level input voltage	$V_{CC} = 2.7 V \text{ to } 3.6 V$		0.8		0.8	V	
VIL		$V_{CC}$ = 4.5 V to 5.5 V		1.65		1.65	v	
VI	Input voltage		0	Vcc	0	VCC	V	
VO	Output voltage		0	VCC	0	VCC	V	
lau		$V_{CC} = 2.7 V \text{ to } 3.6 V$	00	-8		-8		
ЮН	High-level output current	$V_{CC}$ = 4.5 V to 5.5 V	<b>A</b> 0	-16		-16	mA	
1		V <sub>CC</sub> = 2.7 V to 3.6 V	Q	8		8	~ ^	
IOL	Low-level output current	$V_{CC}$ = 4.5 V to 5.5 V		16		16	mA	
$\Delta t/\Delta v$	Input transition rise or fall rate		0	100	0	100	ns/V	
Τ <sub>Α</sub>	Operating free-air temperature		-55	125	-40	85	°C	

NOTE 4: Unused inputs must be held high or low to prevent them from floating.

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED		+	SN	154LV37	'4	SN				
PARAMETER	TEST CONDITIONS	vcc <sup>†</sup>	MIN	TYP	MAX	MIN	TYP	MAX	UNIT	
	I <sub>OH</sub> = -100 μA	MIN to MAX	V <sub>CC</sub> -0	.2		V <sub>CC</sub> -0.	.2			
VOH	I <sub>OH</sub> = – 8 mA	3 V	2.4			2.4			V	
	I <sub>OH</sub> = – 16 mA	4.5 V	3.6			3.6				
	I <sub>OL</sub> = 100 μA	MIN to MAX			0.2			0.2		
V <sub>OL</sub>	I <sub>OL</sub> = 8 mA	3 V			0.4			0.4	V	
	I <sub>OL</sub> = 16 mA	4.5 V			0.55			0.55		
1.	VI = V <sub>CC</sub> or GND	3.6 V		11	l⁄ ±1			±1	μA	
tı		5.5 V		RE	±1			±1		
107		3.6 V		Q	±5			±5	μA	
loz	$V_{O} = V_{CC}$ or GND	5.5 V		S	±5			±5		
laa		3.6 V	20	Ň	20			20		
lcc	$V_{I} = V_{CC} \text{ or GND}, \qquad I_{O} = 0$	5.5 V	d'a		20			20	μA	
∆ICC	One input at $V_{CC}$ – 0.6 V, Other inputs at $V_{CC}$ or GND	3 V to 3.6 V			500			500	μA	
0		3.3 V		2.5			2.5		~F	
Ci	$V_I = V_{CC}$ or GND	5 V		3			3		pF	
C		3.3 V		7			7			
С <sub>О</sub>	$V_{O} = V_{CC}$ or GND	5 V		8			8		pF	

<sup>†</sup> For conditions shown as MIN or MAX, use the appropriate values under recommended operating conditions.



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#### timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

					SN54LV374						
				5 = 5 V 0.5 V	V <sub>CC</sub> = ± 0.		V <sub>CC</sub> =	2.7 V	UNIT		
			MIN	MAX	MIN	MAX	MIN	MAX			
fclock	Clock frequency		C	45	<u> </u>	40	0	35	MHz		
tw	Pulse duration, CLK high or low		g	0	10		13		ns		
t <sub>su</sub>	Setup time before $CLK^\uparrow$	High or low	7	PR-	10	oR	11		ns		
t <sub>h</sub>	Hold time, data after $CLK^\uparrow$		3	<ul> <li>2</li> </ul>	2	<	2		ns		

#### timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

					SN74LV374						
			۲ <mark>۰۵</mark> کا ± 0.		= ۷ <sub>CC</sub> ± 0.3		V <sub>CC</sub> =	2.7 V	UNIT		
			MIN	MAX	MIN	MAX	MIN	MAX			
fclock	Clock frequency		0	45	0	40	0	35	MHz		
tw	Pulse duration, CLK high or low		9		10		13		ns		
t <sub>su</sub>	Setup time before $CLK\uparrow$	High or low	7		10		11		ns		
t <sub>h</sub>	Hold time, data after $CLK^\uparrow$		3		2		2		ns		

#### switching characteristics over recommended operating free-air temperature range, C<sub>L</sub> = 50 pF (unless otherwise noted) (see Figure 1))

	<b>FROM</b>	70	SN54LV374								
PARAMETER	FROM TO (INPUT) (OUTPUT)		$V_{CC}$ = 5 V ± 0.5 V		$V_{CC}$ = 3.3 V $\pm$ 0.3 V			V <sub>CC</sub> = 2.7 V		UNIT	
			MIN	TYP	MAX	MIN	TYP	MAX	MIN	MAX	
fmax			45	80		40	70		35		MHz
<sup>t</sup> pd	CLK	Q		11	19	C.N.	15	24	EN	29	ns
ten	OE	Q		10	20		13	24	2.	28	ns
<sup>t</sup> dis	OE	Q		8	21		12	24		29	ns

#### switching characteristics over recommended operating free-air temperature range, CL = 50 pF (unless otherwise noted) (see Figure 1)

			SN74LV374								
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>CC</sub> :	$V_{CC}$ = 5 V $\pm$ 0.5 V			$V_{\mbox{CC}}$ = 3.3 V $\pm$ 0.3 V			V <sub>CC</sub> = 2.7 V	
			MIN	TYP	MAX	MIN	TYP	MAX	MIN	MAX	
fmax			45	80		40	70		35		MHz
<sup>t</sup> pd	CLK	Q		11	19		15	24		29	ns
ten	OE	Q		10	20		13	24		28	ns
<sup>t</sup> dis	OE	Q		8	21		12	24		29	ns



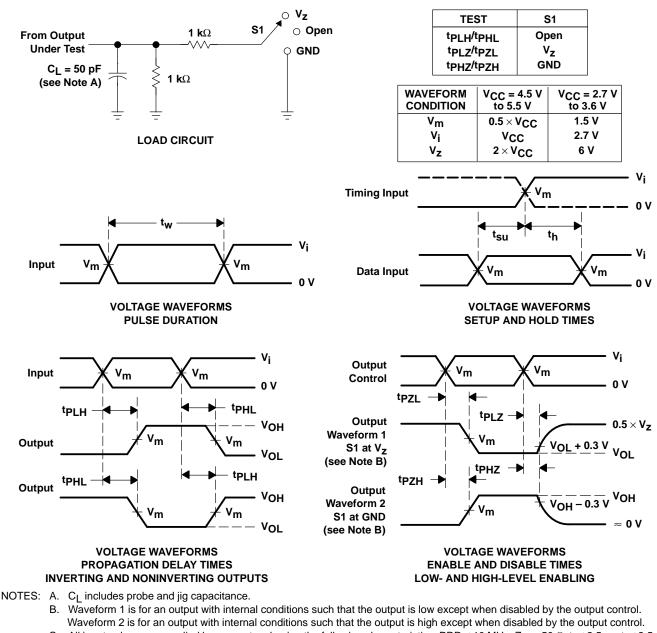
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operating characteristics,  $T_A = 25^{\circ}C$ 

	PARAMETER	TEST CONDITIONS	Vcc	TYP	UNIT	
	Outputs enabled		3.3 V	52		
	Power dissipation canacitance per flip flep	Per dissipation capacitance per flip-flop Outputs disabled $C_1 = 50 \text{ pF}, \text{ f} = 10 \text{ MHz}$		34	рF	
C <sub>pd</sub>	Power dissipation capacitance per hip-hop	Outputs enabled	$O_{L} = 50 \text{ pr},  I = 10 \text{ Wirlz}$	5 V	60	יץ
		Outputs disabled	57	35		

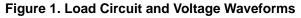


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#### PARAMETER MEASUREMENT INFORMATION

- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz, Z<sub>O</sub> = 50  $\Omega$ , t<sub>f</sub>  $\leq$  2.5 ns, t<sub>f</sub>  $\leq$  2.5 ns.
  - D. The outputs are measured one at a time with one transition per measurement.
  - E.  $t_{PLZ}$  and  $t_{PHZ}$  are the same as  $t_{dis}$ .
  - F.  $t_{PZL}$  and  $t_{PZH}$  are the same as  $t_{en}$ .
  - G.  $t_{PLH}$  and  $t_{PHL}$  are the same as  $t_{pd}$ .





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